

<b>Notice of References Cited</b>		Application/Control No. 10/562,327	Applicant(s)/Patent Under Reexamination TAKENAKA ET AL.	
		Examiner JONATHAN SAMPLE	Art Unit 4184	Page 1 of 1

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*	C	US-5,644,204	07-1997	Nagle, John	318/568.12
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#### NON-PATENT DOCUMENTS

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